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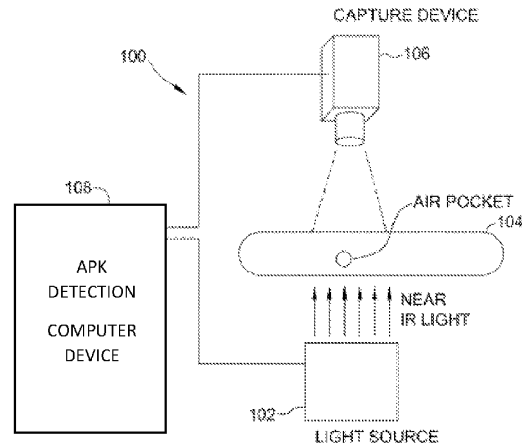
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(54) Title: SYSTEMS AND METHODS FOR AIR POCKET DEFECT DETECTION

FIG. 1



(57) Abstract: A computer device (108; 802) includes at least one processor (805) in communication with at least one memory device (810). The at least one processor (805) is programmed to: receive (505) at least one image (118, 128) of a material to be analysed (104); execute (510) a plurality of models (410, 420, 430) trained to classify the at least one image (118, 128) to detect a first defect type; receive (515) from each of the plurality of models (410, 420, 430) a prediction (415, 425, 435) that the at least one image (118, 128) includes the first defect type; combine (520) the plurality of predictions (415, 425, 435) to calculate a final prediction (445) of whether or not the at least one image (118, 128) includes the first defect type; and reject or approve (525) the material to be analysed (104) based upon the final prediction (445).

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